



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:  
Yongjun J. Hu

Serial No.: 10/719,047

Filed: November 20, 2003

For: **METHOD AND STRUCTURE FOR  
REDUCING RESISTANCE OF A  
SEMICONDUCTOR DEVICE FEATURE**

§  
§ Group Art Unit: 2822  
§  
§ Examiner: Mark V. Prenty  
§  
§ Atty. Docket: 2003-0930.00/US  
§  
§ Confirmation No.: 3287  
§  
§  
§

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P.O. Box 1450  
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I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail, postage prepaid, in an envelope addressed to:  
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August 5, 2005  
Date

Maria J. Fulp  
Signature

**COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE**

Applicant submits that each one of the claims of the captioned application is allowable over the cited art for reason of the cited art failing to disclose or suggest the features and/or combination of features as are defined therein. Although applicant acknowledges the Examiner's "Statement of Reasons for Allowance" as set forth with the Notice of Allowance mailed May 5, 2005, applicant submits that the reasons for allowance as provided by the Examiner may represent merely a portion of all of the reasons that support the patentability of the claims of the present application without necessarily being exhaustive.

If there are any matters which may be resolved or clarified through a telephone call, the Examiner is cordially invited to contact the undersigned.

Respectfully submitted,

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